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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/537,868	06/07/2005	Yoshiaki Hasegawa	OKUDP0116US	8395
51921 MARK D. SAR	7590 03/08/2007 ALINO (MEI)	EXAMINER		
RENNER, OTT	O, BOISSELLE & SKLA	INGHAM, JOHN C		
1621 EUCLID AVENUE 19TH FLOOR CLEVELAND, OH 44115			ART UNIT	PAPER NUMBER
			2814	
SHORTENED STATUTORY	Y PERIOD OF RESPONSE	MAIL DATE	DELIVER	Y MODE
3 MON	NTHS	03/08/2007	PAF	PER

Please find below and/or attached an Office communication concerning this application or proceeding.

If NO period for reply is specified above, the maximum statutory period will apply and will expire 6 MONTHS from the mailing date of this communication.

"		Application No.	Applicant(s)		
Office Action Summary		10/537,868	HASEGAWA ET AL.		
		Examiner	Art Unit		
		John C. Ingham	2814		
	he MAILING DATE of this communication app	ears on the cover sheet with the	e correspondence address		
Period for R	• •	/ 10 OFT TO EVOIDE * MONT	(C), CD THIDTY (CC), DAYO		
WHICHE - Extension after SIX - If NO peri - Failure to Any reply	TENED STATUTORY PERIOD FOR REPLY EVER IS LONGER, FROM THE MAILING DATE of time may be available under the provisions of 37 CFR 1.13 (6) MONTHS from the mailing date of this communication. Od for reply is specified above, the maximum statutory period we reply within the set or extended period for reply will, by statute, received by the Office later than three months after the mailing atent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION ATE OF THIS COMMUNICA	ON. timely filed om the mailing date of this communication. NED (35 U.S.C. § 133).		
Status					
1)⊠ Re	esponsive to communication(s) filed on 17 De	ecember 2006.			
		action is non-final.			
3) <u></u> Sir	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is				
clo	sed in accordance with the practice under E	x parte Quayle, 1935 C.D. 11,	453 O.G. 213.		
Disposition	of Claims				
4)⊠ Cla	aim(s) <u>1,4-14 and 16-19</u> is/are pending in the	e application.			
	Of the above claim(s) is/are withdraw	• •			
5)□ Cla	aim(s) is/are allowed.				
6)⊠ Cla	aim(s) <u>1,4-14 and 16-19</u> is/are rejected.				
7) 🗌 Cla	aim(s) is/are objected to.				
8)∏ Cla	aim(s) are subject to restriction and/or	election requirement.			
Application	Papers				
	specification is objected to by the Examiner				
	e drawing(s) filed on <u>07 June 2005</u> is/are: a)		to by the Examiner.		
	plicant may not request that any objection to the				
Re	placement drawing sheet(s) including the correcti	on is required if the drawing(s) is o	objected to. See 37 CFR 1.121(d).		
11) <u></u> Th∈	e oath or declaration is objected to by the Ex	aminer. Note the attached Office	ce Action or form PTO-152.		
Priority und	er 35 U.S.C. § 119				
12)⊠ Ack	nowledgment is made of a claim for foreign	priority under 35 U.S.C. § 119((a)-(d) or (f).		
a)⊠ <i>A</i>	All b)☐ Some * c)☐ None of:				
1.[Certified copies of the priority documents	s have been received.			
2.[Certified copies of the priority documents	have been received in Applica	ation No		
3.[Copies of the certified copies of the prior	ity documents have been recei	ved in this National Stage		
	application from the International Bureau	. , ,,			
* See	the attached detailed Office action for a list of	of the certified copies not receive	ved.		
Attachment(s)					
	References Cited (PTO-892) Draftsperson's Patent Drawing Review (PTO-948)	4) ∐ Interview Summa Paper No(s)/Mail			
3) 🔲 Informatio	on Disclosure Statement(s) (PTO/SB/08)	5) 🔲 Notice of Informal			
Paper No	(s)/Mail Date	6)			

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DETAILED ACTION

1. The amendments to the claims filed 17 December 2006 have been entered.

Claim Objections

2. Claim 13 is objected to because of the following informalities: "the two overhanging portions" lacks antecedent basis. Appropriate correction is required.

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).
- 5. Claims **1, 4-14 and 16-19** are rejected under 35 U.S.C. 103(a) as being unpatentable over Goto (US 6,522,676) and Sirbu (US 6,542,531).

6. Regarding claims 1, 4-5 and 7, Goto discloses in Fig 6 a semiconductor lightemitting element comprising: a first group II-V compound semiconductor (5a); a current confining layer (6), which is made of a second group III-V compound semiconductor that has grown on a selected surface area of the first group III-V compound semiconductor and which has a striped opening (see Fig 1) extending along the length of a resonant cavity; and a third group III-V compound semiconductor (5b), which covers the surface of the first group III-V compound semiconductor that is exposed through the striped opening and the surface of the current confining layer, wherein the group III-V compound semiconductors are gallium nitride based (col 8 In 10-17), and wherein the current confining layer (6) has two overhanging portions (above area 52) that overhang toward the striped opening, wherein a gap (filled by 52) is provided between each of the two overhanging portions of the current confining layer and a part of the surface of the first group III-V compound semiconductor (5a), wherein the gap has a height of 0.1µm and a width of 0.5µm (col 8 In 46-51) and wherein a portion of the third group III-V compound semiconductor (5b), which contacts with the surface of the first group III-V compound semiconductor through the striped opening has a width of 2.5µm (W2).

Goto does not specify that the gap is unfilled by the third group III-V compound semiconductor. However, Sirbu teaches in Fig 1A that air gaps are used on either side of a current aperture in order to restrict current flow and vary the index of refraction within the active region (col 4 ln 28-35). It would have been obvious to one of ordinary skill in the art at the time of the invention to use the teaching of Sirbu on the device of Goto in order to vary the index of refraction within the active region.

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7. Regarding claim **6**, Goto discloses in Fig 6 the element of claim 1 wherein the first group III-V compound semiconductor has a multilayer structure (3, 4, 5a) including an active layer (4).

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- 8. Regarding claim **8**, Goto discloses in Fig 6 the element of claim 7 wherein the current confining layer (6) is AlGaN and has a thickness of 0.3µm (col 8 ln 16, 30).
- 9. Regarding claims **9-11**, Goto discloses in Fig 6 the element of claim 1 wherein the conductivity of the first (5a) and third (5b) group III-V compound semiconductors is the same (p type), and wherein the conductivity of the second group III-V compound semiconductor is opposite (n type).
- 10. Regarding claim **12, 16 and 18**, Goto discloses in Fig 8 a method for fabricating a semiconductor light-emitting element, the method comprising the steps of: (step a) providing a striped masking layer (15), with a width set to 2.5µm, on a first Group III-V compound semiconductor (56a); selectively growing a second Group III-V compound semiconductor (6) over the entire surface of the first group III-V compound semiconductor except a portion covered with the masking layer, thereby forming a current confining layer that has a striped opening defined by the masking layer (step b) and overhanging portions that overhang the striped opening; selectively removing the masking layer; and growing a third Group III-V compound semiconductor (56b), to cover the surface of the first group III-V compound semiconductor (which is exposed through the striped opening at a portion with a width of 2µm) and the surface of the current confining layer (step c), wherein the growing of the third group III-V compound semiconductor includes providing gaps between the first group III-V compound

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semiconductor (56a) and the overhanging portions (portions of 6 above areas 52), and wherein the group III-V compound semiconductors are gallium nitride based (col 8 In 10-17).

Goto does not specify that the gap is unfilled by the third group III-V compound semiconductor. However, Sirbu teaches in Fig 1A that air gaps are used on either side of a current aperture in order to restrict current flow and vary the index of refraction within the active region (col 4 ln 28-35). It would have been obvious to one of ordinary skill in the art at the time of the invention to use the teaching of Sirbu in the method of Goto in order to vary the index of refraction within the active region.

- 11. Regarding claim **13**, Goto discloses in Fig 8(b) the method of claim 12 wherein the step of selectively growing a second group III-V compound semiconductor (6) includes growing laterally toward the center of the masking layer, thereby defining two overhanging portions for the current confining layer (col 9 In 7-17).
- 12. Regarding claim **14**, Goto discloses in Fig 8(c) the method of claim 13 wherein the removal of the masking layer includes removing parts of the masking layer (15), which are located under the overhanging portions of the current confining layer (6), thereby making the overhanging portions (area 52) overhang toward the center of the striped opening.
- 13. Regarding claim **17**, Goto discloses in Fig 6 the element of claim 1 wherein the first group III-V compound semiconductor has a multilayer structure (3, 4, 5a) including an active layer (4).

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14. Regarding claim **19**, Goto discloses in Fig 6 the element of claim 7 wherein the current confining layer (6) is AlGaN and has a thickness of 0.3µm (col 8 ln 16, 30).

Response to Arguments

15. Applicant's arguments with respect to claims 1-19 have been considered but are moot in view of the new ground(s) of rejection.

Conclusion

16. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to John C. Ingham whose telephone number is (571) 272-8793. The examiner can normally be reached on M-F, 8am-5pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael Fahmy can be reached on (571) 272-1705. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

John C Ingham Examiner Art Unit 2814

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HOWARD WEISS